

Effect of Lowering Curing Temperature of Electrically Conductive Adhesives on Ribbon Connected Solar Cells

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Introduction

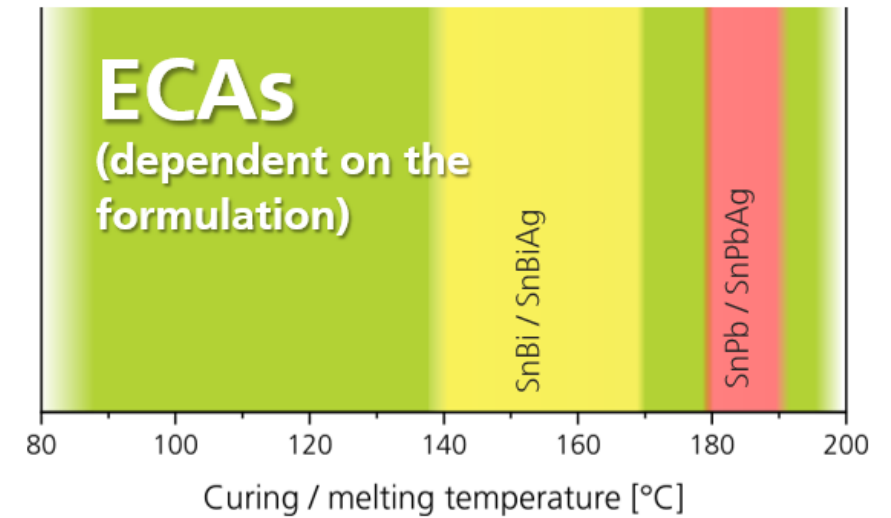
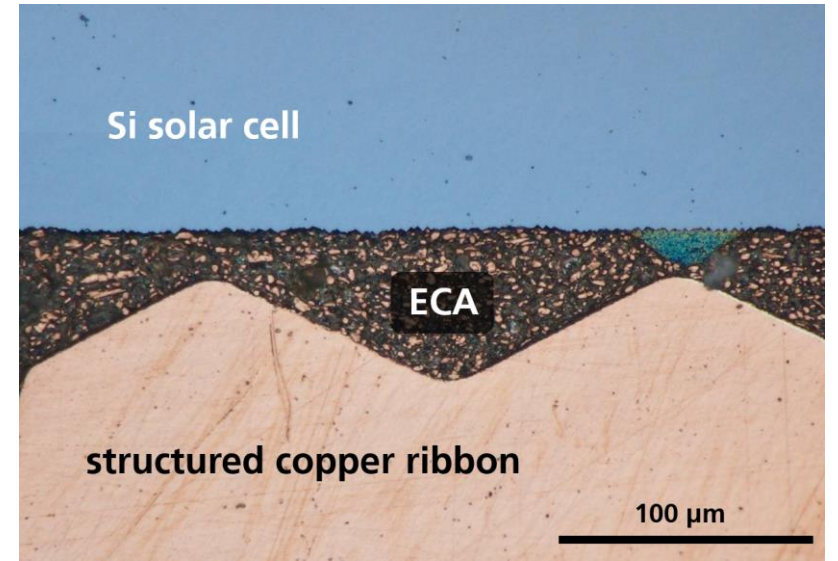
Electrically Conductive Adhesives (ECAs)

Working principle

- ECAs consist of a polymer matrix with conductive filler (typically Ag)
- Conductive paths are formed upon curing
- Thermal curing – most common in PV

Advantages of ECAs for solar cell interconnection

- Possibility to tailor the characteristics to process requirements (Rheology, curing scheme, conductive filler type, etc.)
- No busbar metallization required → 1BO.4.1 (Tuesday)
- Wide processing window in terms of temperature
- Compatibility with temperature sensitive high-efficiency cell types like perovskite-Si tandem (PVST)



Introduction

Perovskite-Silicon Tandem Cells (PVST)

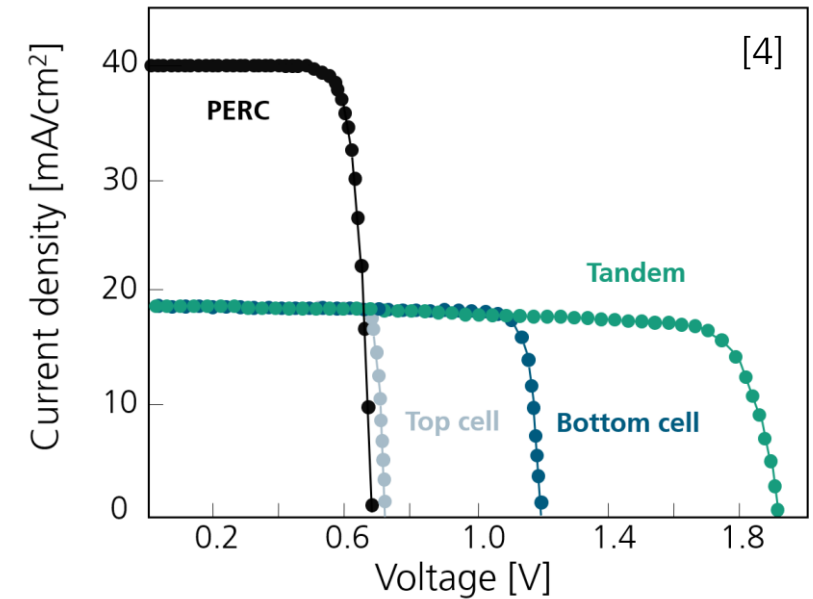
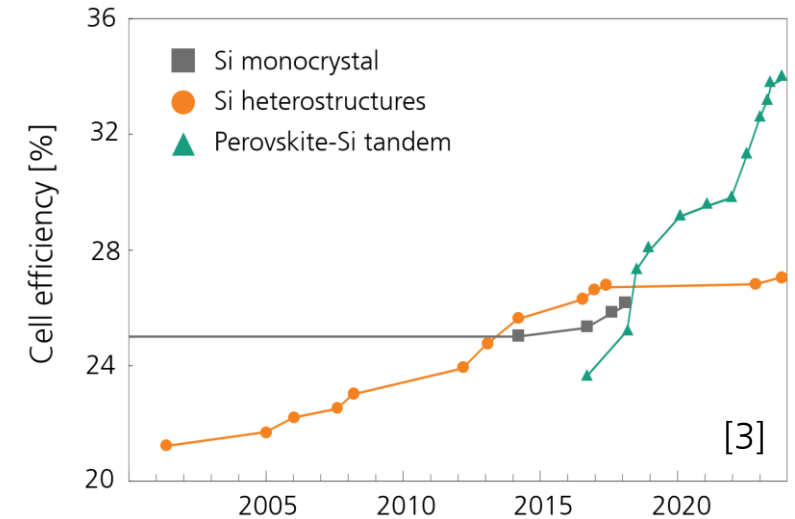
- Current PVST efficiency record: 34.6 % (lab device) and 30.1 % (M6) [1]
- Expected to appear at the market after 2025 with efficiencies ~26 % [2]

Advantages

- High power conversion efficiency (PCE) potential and steep learning curve
- Low current density → less power loss attributed to series resistance
- Potential to reduce silver consumption per Watt due to relaxed metallization requirements

Two main challenges of ECA interconnection of PVST

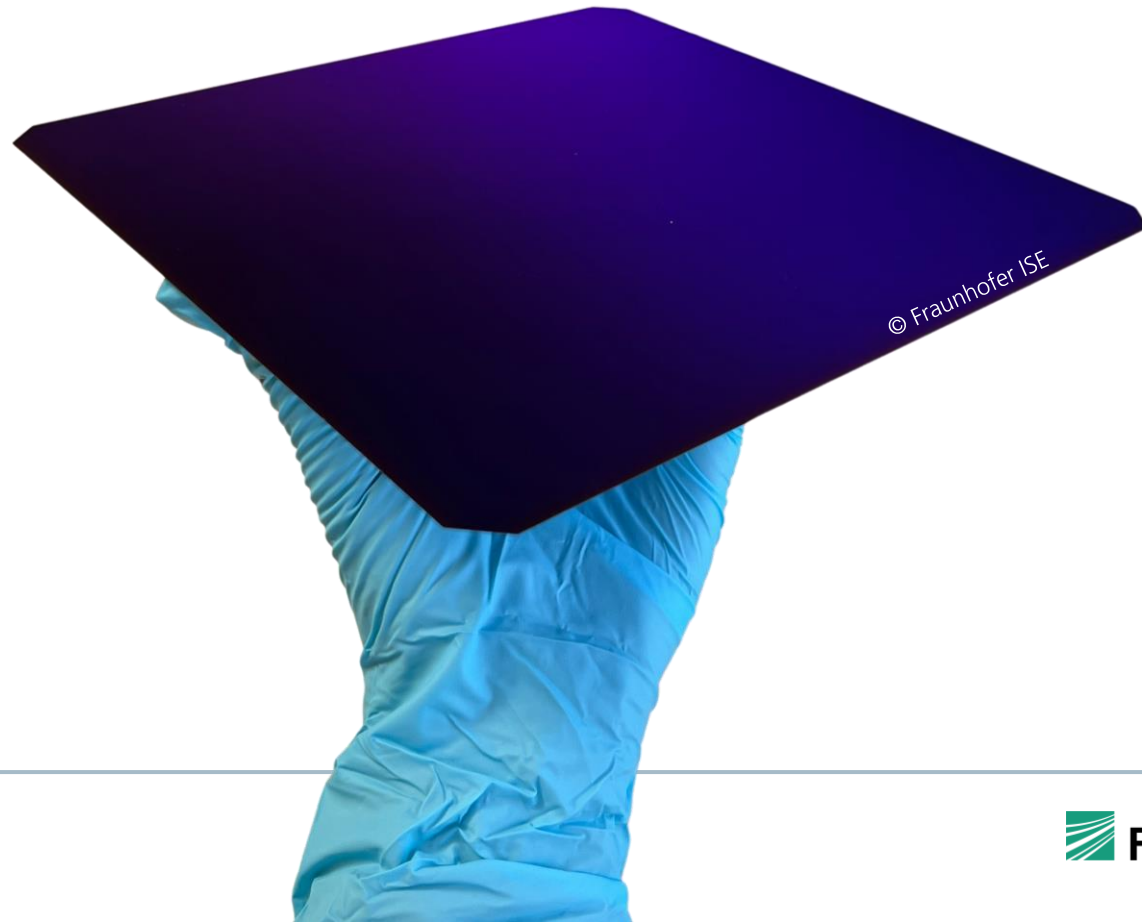
- Low process temperature required → ECA
- Silver reduction



Silver Consumption in a PVST Module

Silver-containing module components

- Bifacial M6 (166 mm × 166 mm) wafer is considered

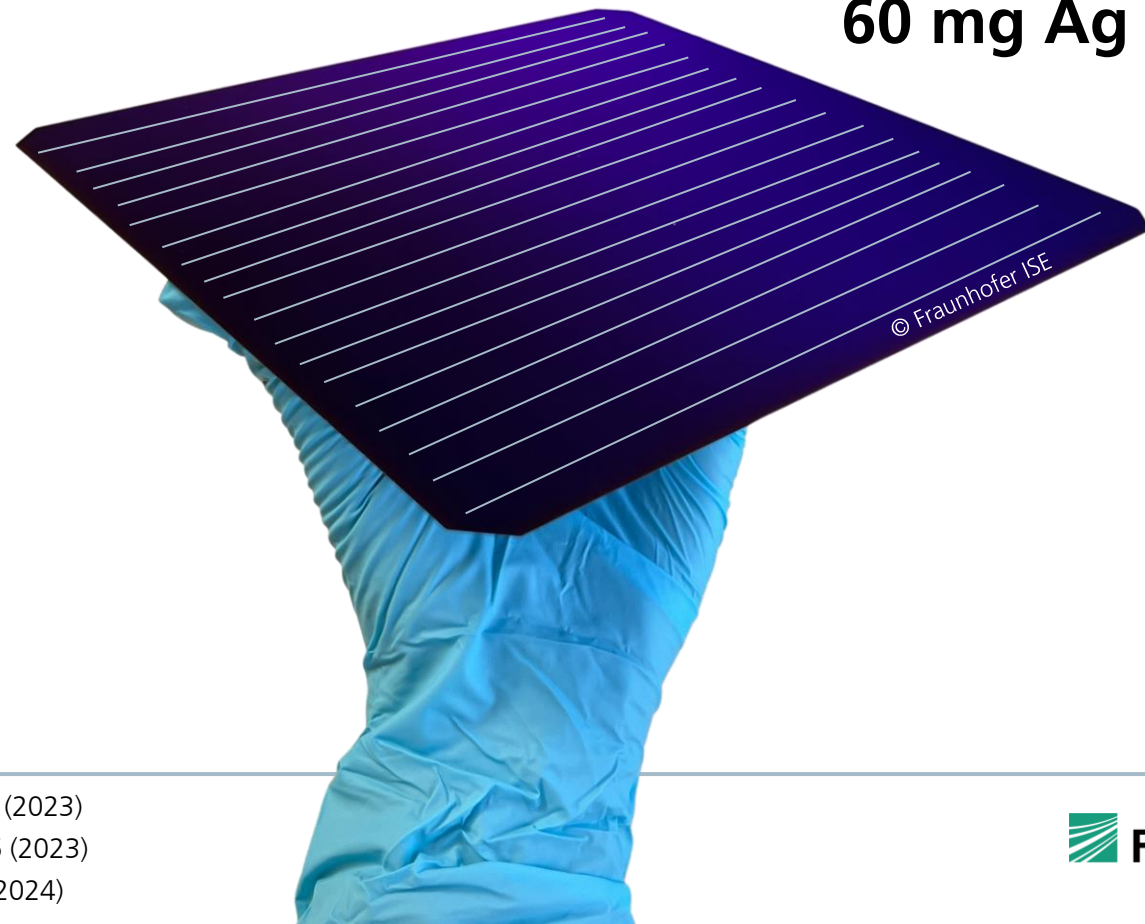


Silver Consumption in a PVST Module

Metallization Fingers

Silver-containing module components

- Fingers (bifacial cell)
 - Front – 60 pcs. [5]
 - Rear – 120 pcs.
 - Finger width = 25 μm [6]
 - Finger height = 8 μm [7]

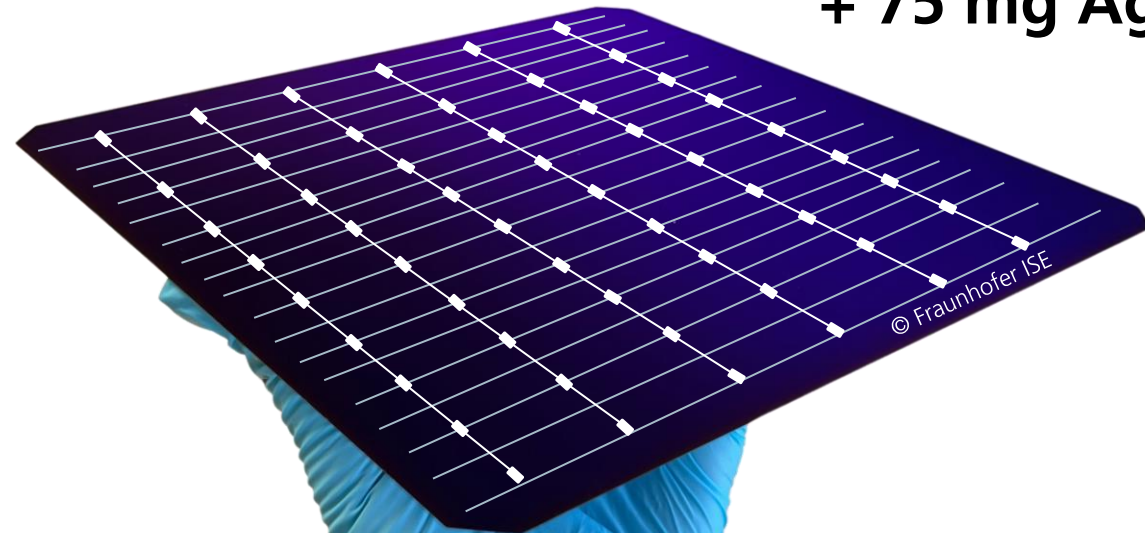


Silver consumption in a PVST module

Busbar metallization

Silver-containing module components

- Fingers (bifacial cell)
- Busbars
 - 6 busbars [8]
 - Busbar design - redundancy line with interconnection pads



60 mg Ag
+ 75 mg Ag

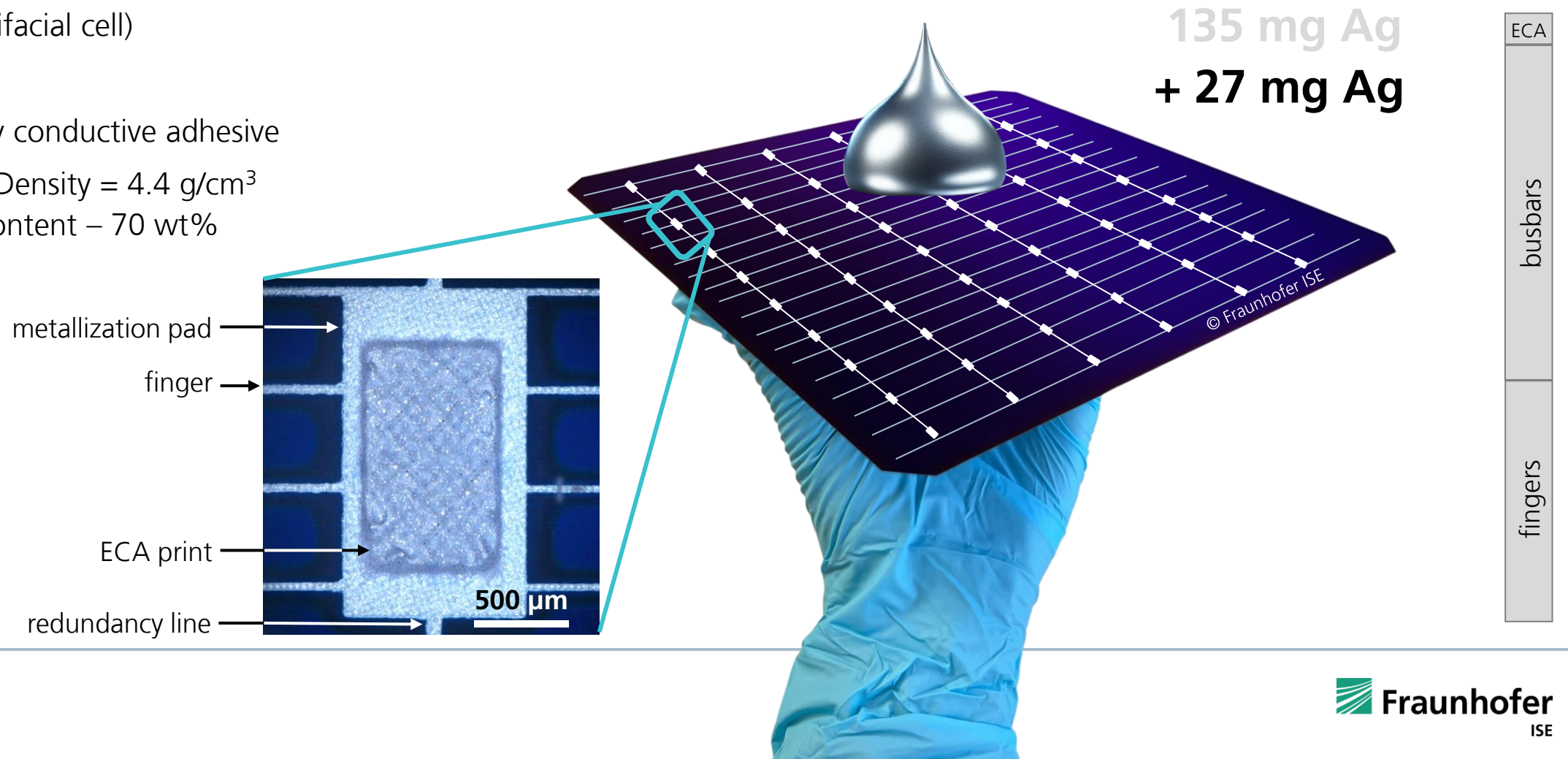


Silver Consumption in a PVST Module

Electrically Conductive Adhesive

Silver-containing module components

- Fingers (bifacial cell)
- Busbars
- Electrically conductive adhesive
 - ECA Density = 4.4 g/cm^3
 - Ag content – 70 wt%



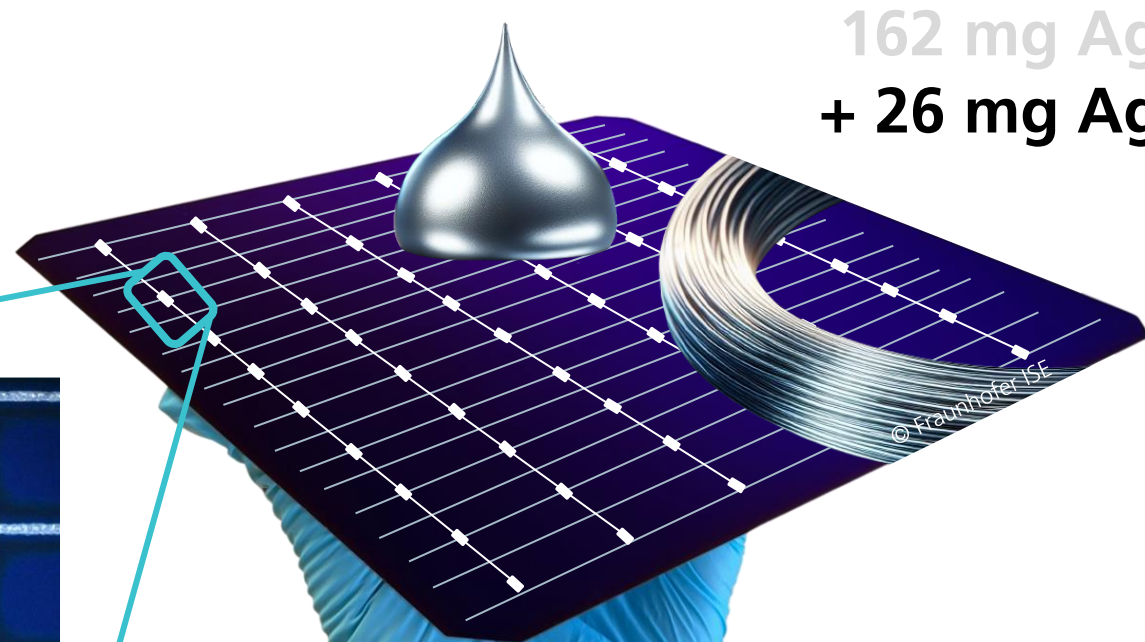
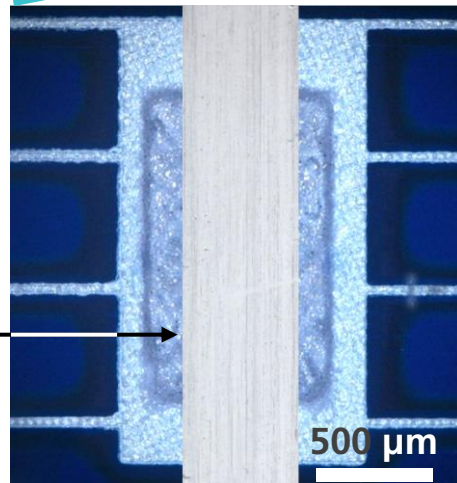
Silver Consumption in a PVST Module

Interconnector

Silver-containing module components

- Fingers (bifacial cell)
- Busbars
- Electrically conductive adhesive
- Interconnector
 - Flat ribbon
 - 1 μm Ag coating

Silver-coated interconnector

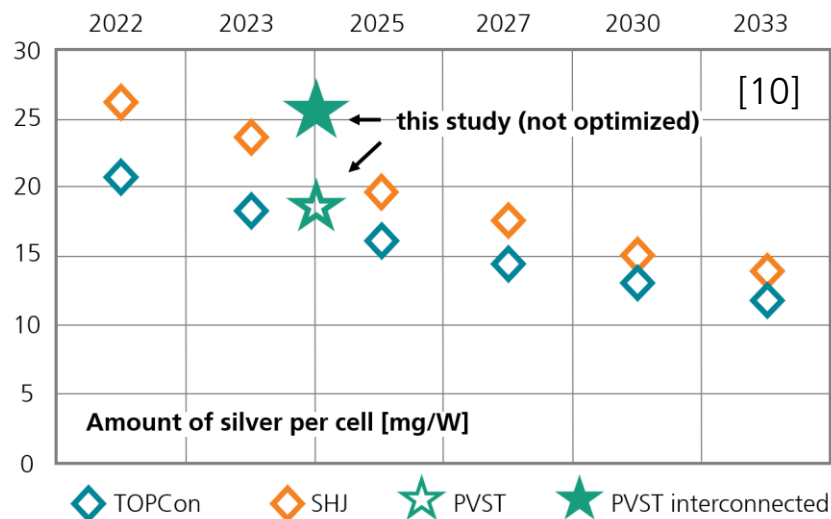


ribbon
ECA
busbars
fingers

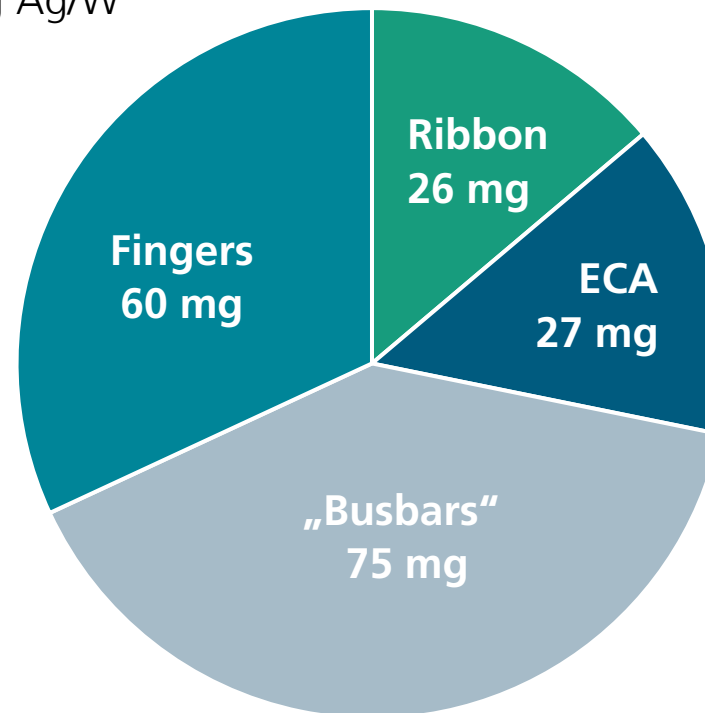
Silver Consumption in a PVST Module

Overview

- Ag consumption / cell power
 - PVST M6 cell → ~ 19 mg Ag/W
 - PVST M6 cell + ECA interconnection → ~ 27 mg Ag/W

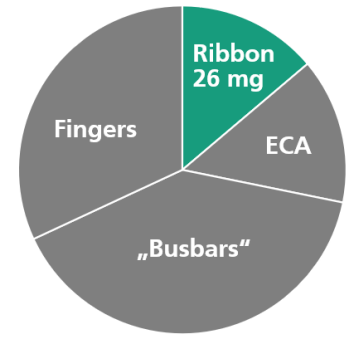


188 mg Ag / M6 cell

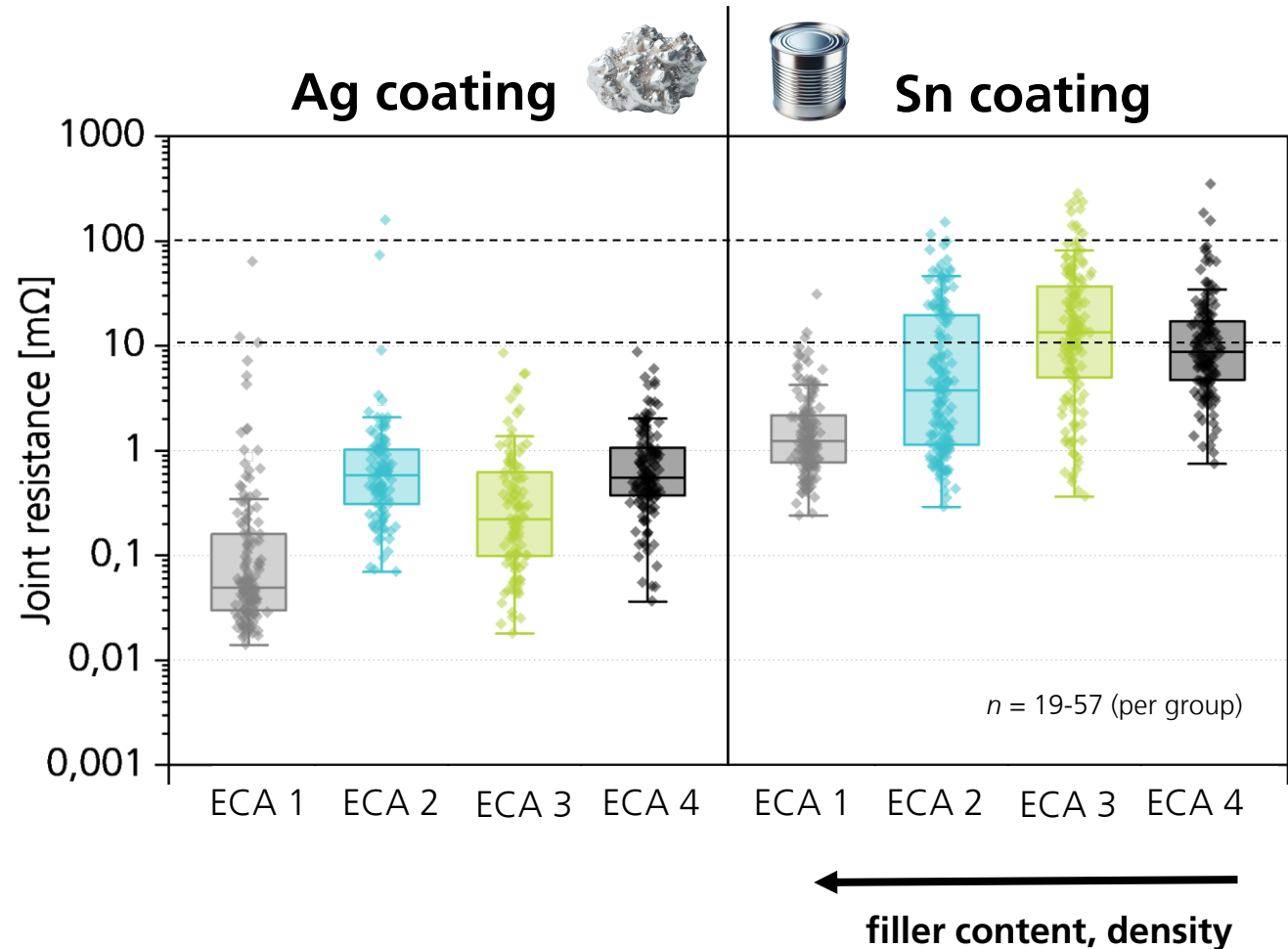
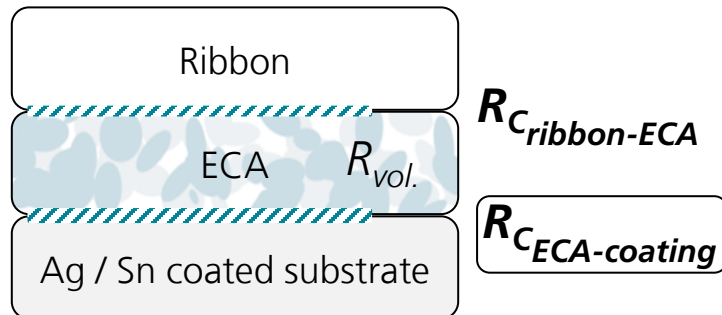


Low-Temperature Interconnection with Sn-Coated Ribbons

Joint Resistance

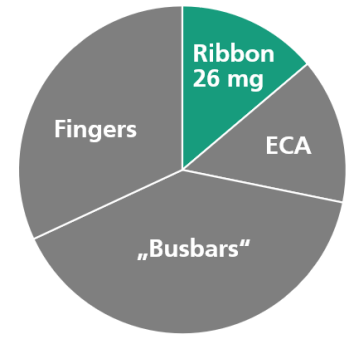


Overall higher R_{joint} for Sn coating is observed



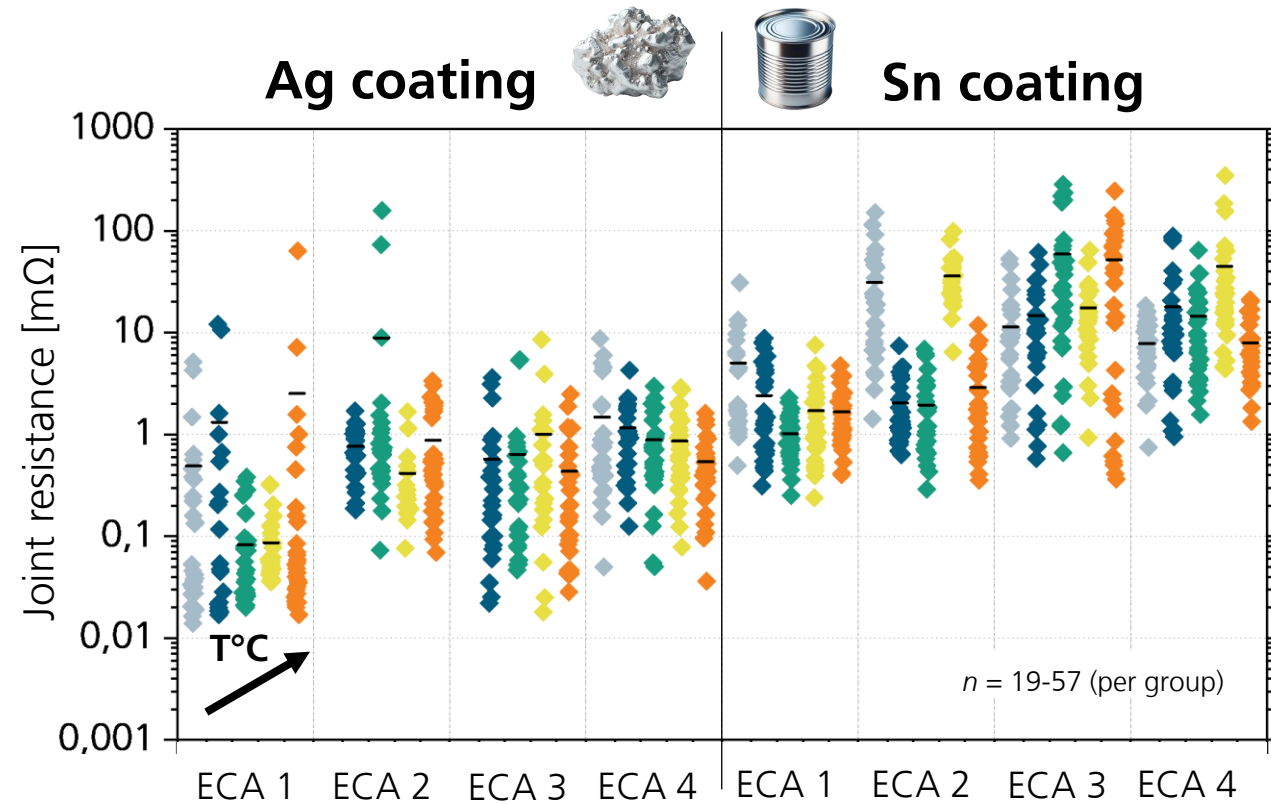
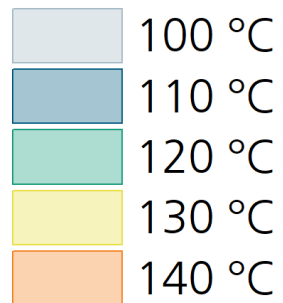
Low-Temperature Interconnection with Sn-Coated Ribbons

Joint Resistance



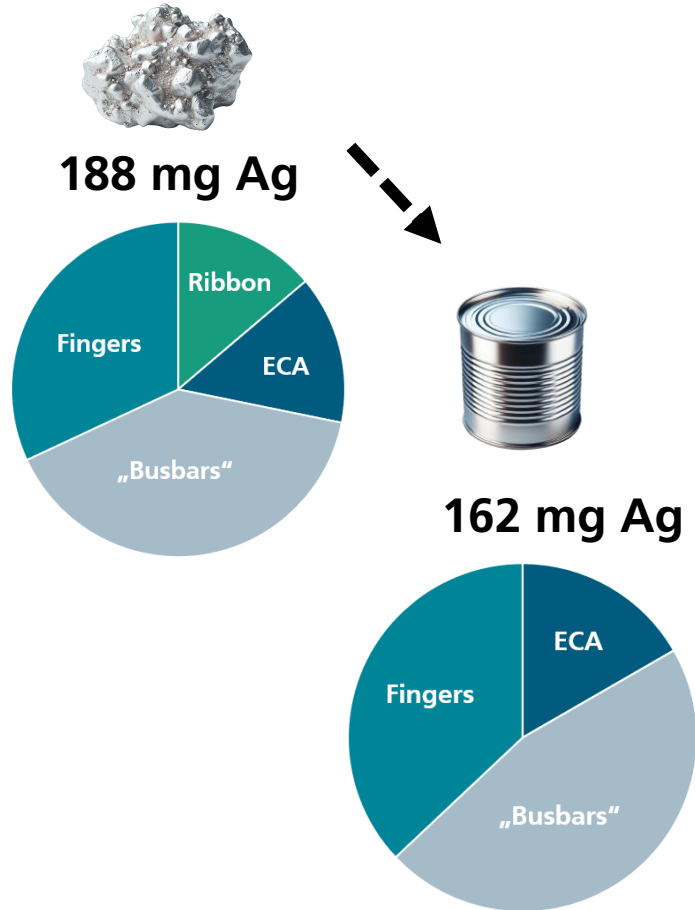
Due to strong R_{joint} scattering, **no trends related to curing temperature** of the ECAs can be determined

Curing T°C:



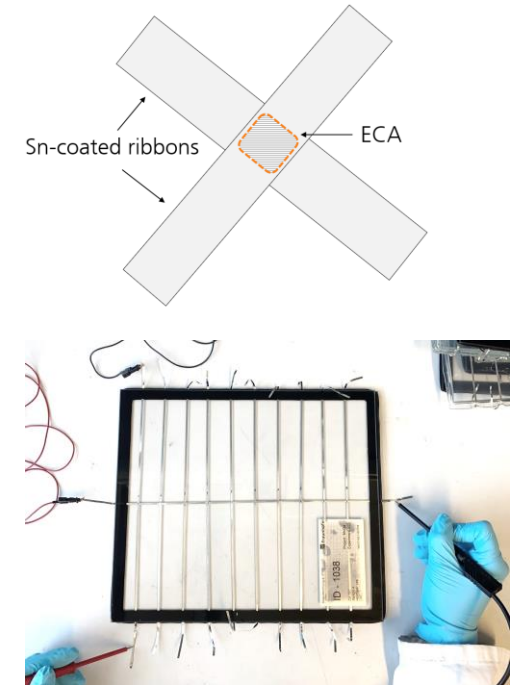
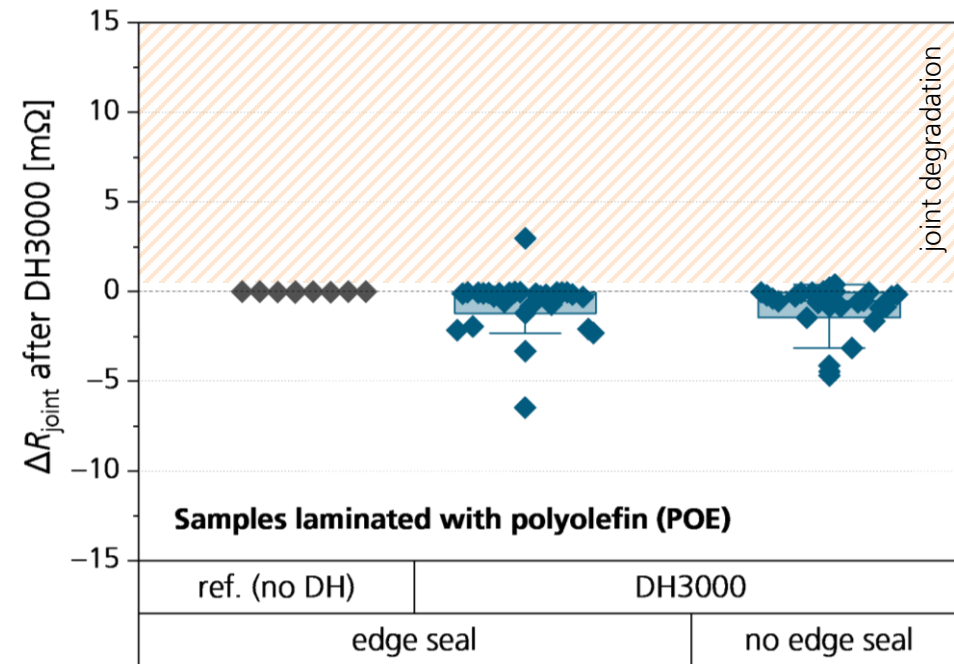
Potential for Ag Reduction

Sn Ribbon Coating



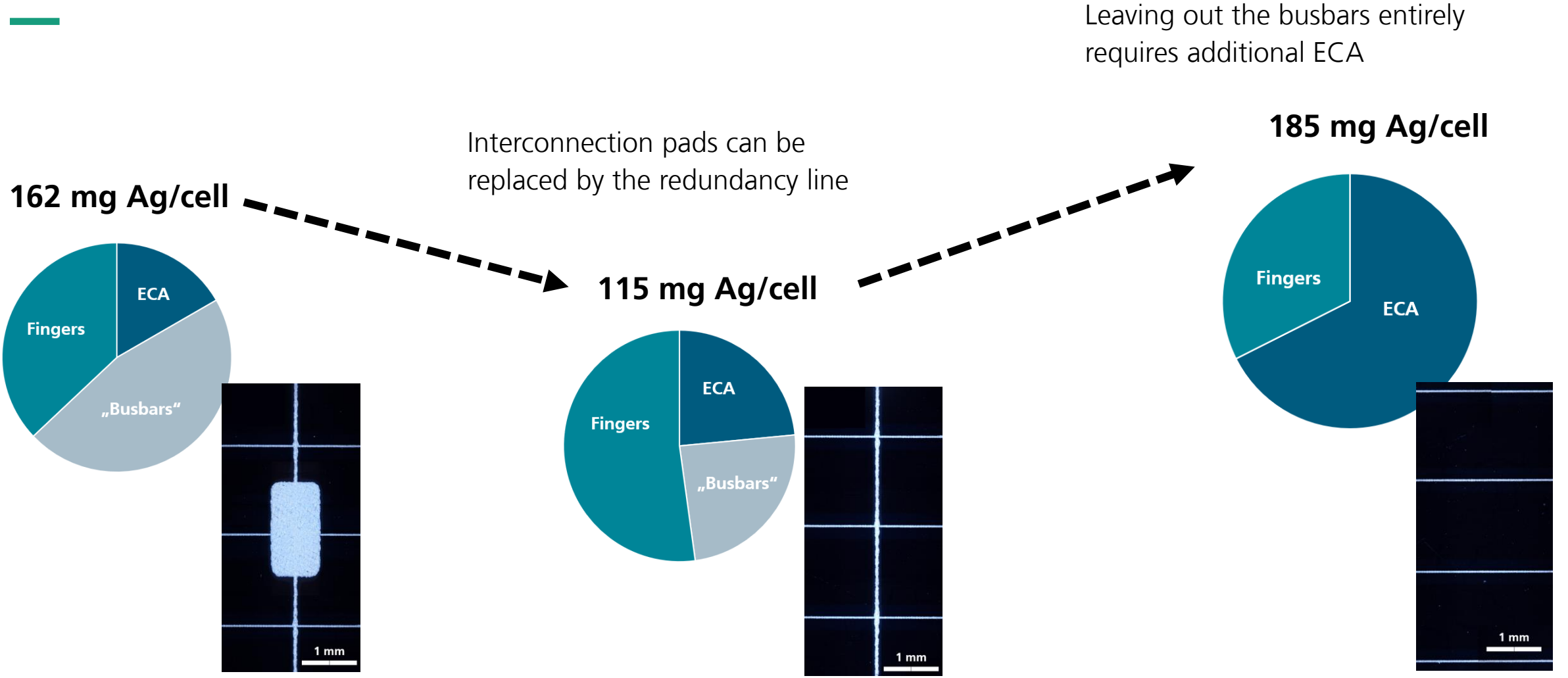
Ag interconnector coating can be replaced by Sn

- Galvanic corrosion* risk is low in solar modules
- POE module encapsulation (low WVTR) and edge seal facilitates joint protection
- Sn / Ag-based ECA / Sn joints show no joint degradation after DH3000



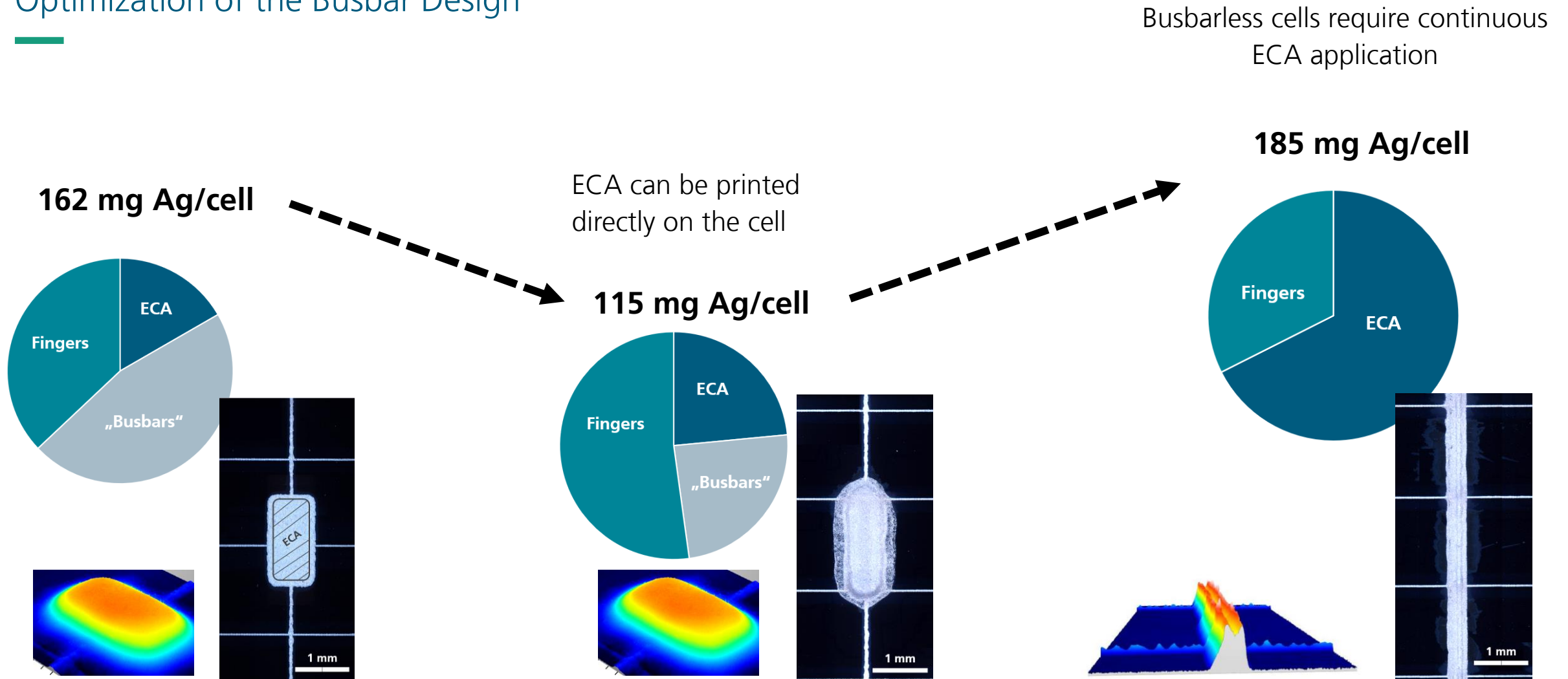
Potential for Ag Reduction

Optimization of the Busbar Design



Potential for Ag Reduction

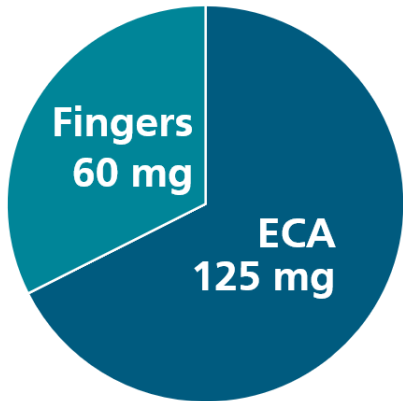
Optimization of the Busbar Design



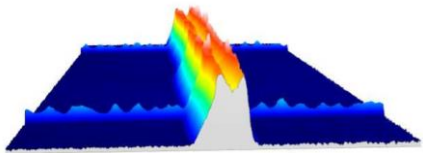
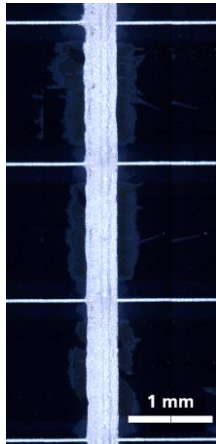
Potential for Ag Reduction

Optimization of the ECA silver content (busbarless)

185 mg Ag/cell

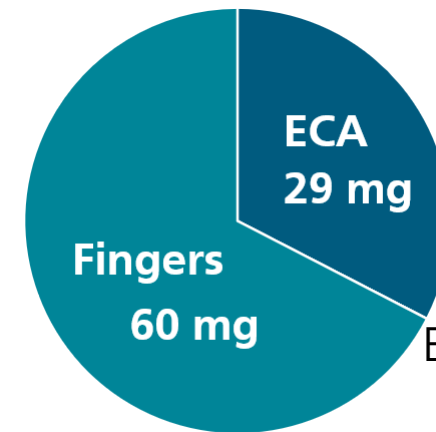


ECA Density = 4.4 g/cm^3
Ag content – 70 wt%



- Significant Ag reduction by using ECA with low Ag content
- When metallization between fingers is absent, conductivity of the ECA is crucial

89 mg Ag/cell

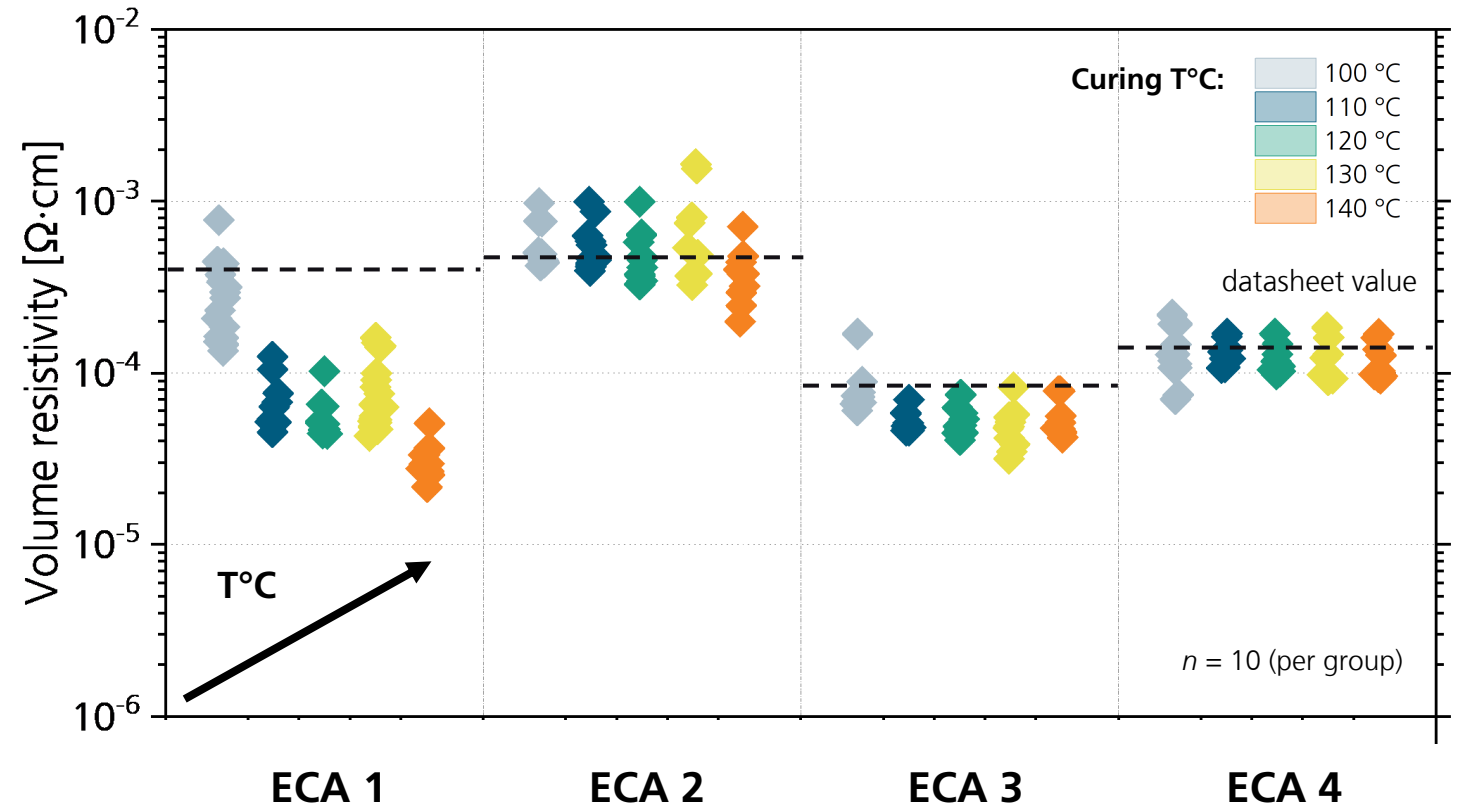


busbarless cell
ECA Density = 4.2 g/cm^3
Ag content – 17 wt%

Conductivity of the ECAs

Effect of Curing Temperature

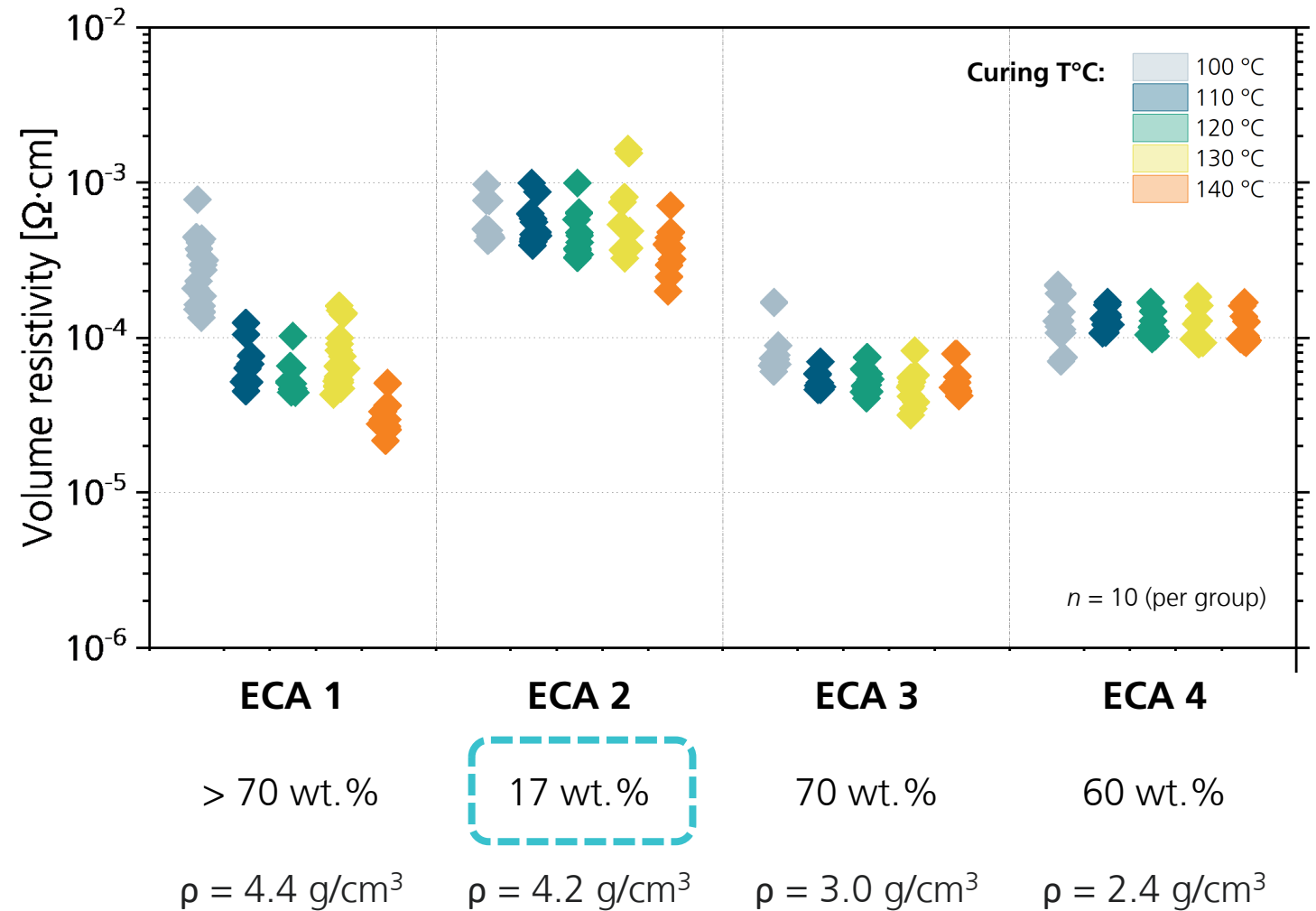
- ECA 1 - ECA 3: curing at higher temperature results in lower volume resistivity
- ECA 4: volume resistivity is not influenced by the curing temperature



Conductivity of the ECAs

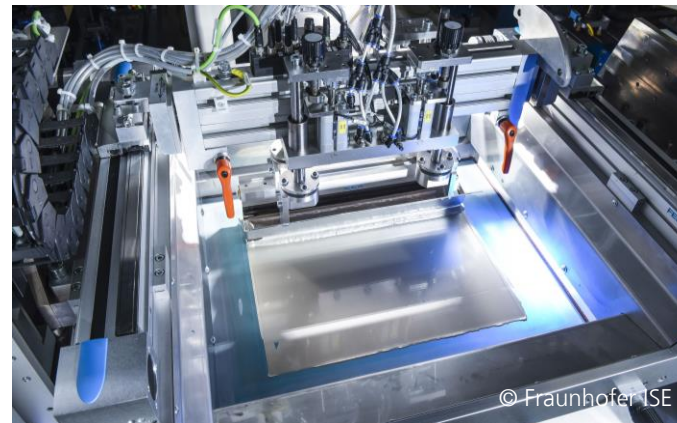
Effect of Silver Content

- ECAs with higher silver content demonstrate lower volume resistivity
- ECA 2 (Cu/Ag filler) shows $R_{vol.} < 10^{-2} \Omega \cdot cm \rightarrow$ value compatible with solar cell interconnection



Low-Temperature ECA Interconnection Performance

Sample Production

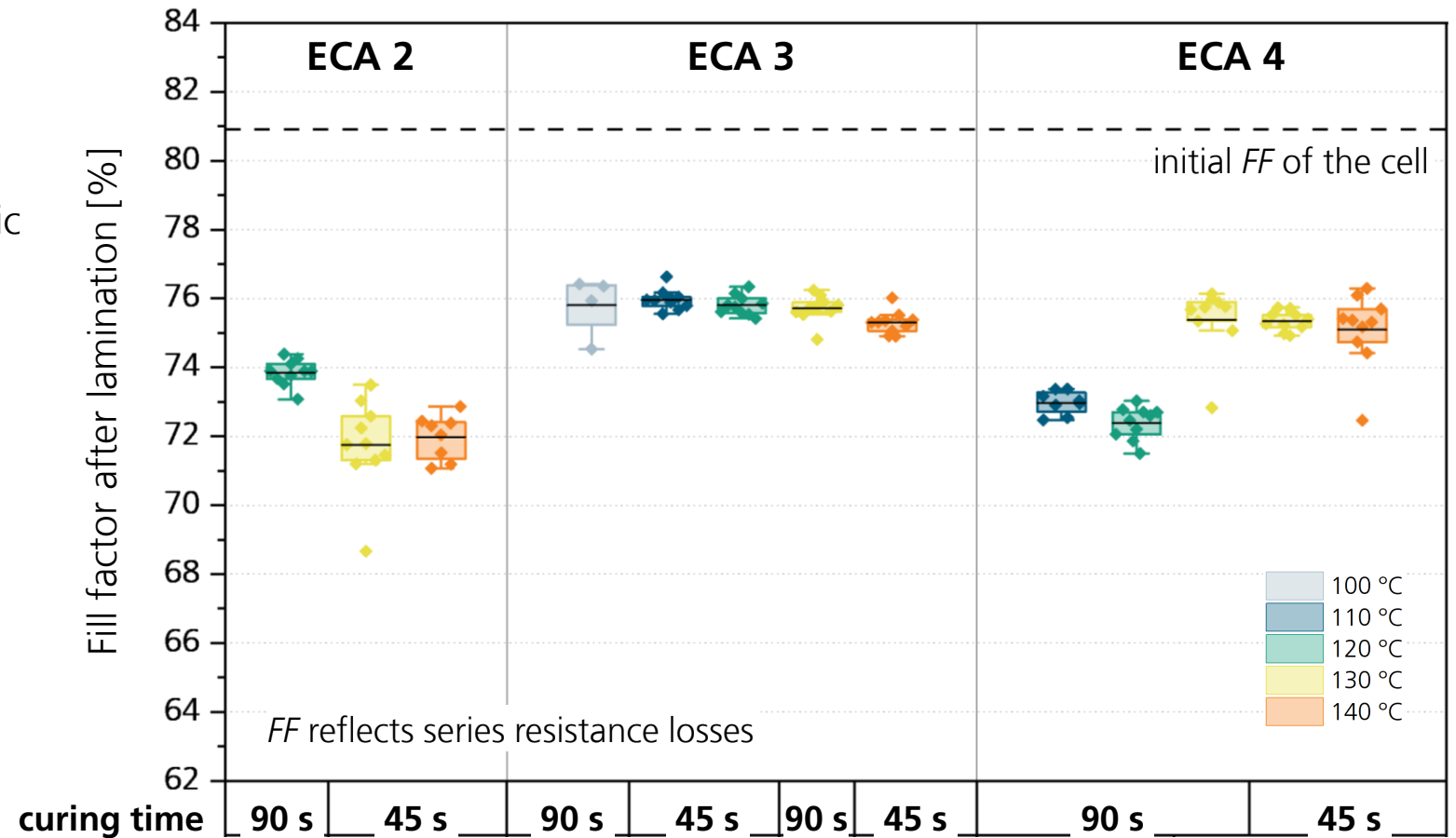


- Automatic interconnection with Ag-coated ribbons
- Curing schemes compatible with industrial PVST cell interconnection
 - $T \leq 140 \text{ }^\circ\text{C}$
 - $t \leq 90 \text{ sec}$
- Application of ECA with the integrated screen printer
- Continuous design to ensure current transport between metallization fingers
- ECA interconnection of busbarless SHJ cells
- ECA silver consumption* (differs due to different Ag content)
 - ECA 2: 40 mg
 - ECA 3: 119 mg
 - ECA 4: 82 mg

Low-Temperature ECA Interconnection Performance in the Module

After Module Production

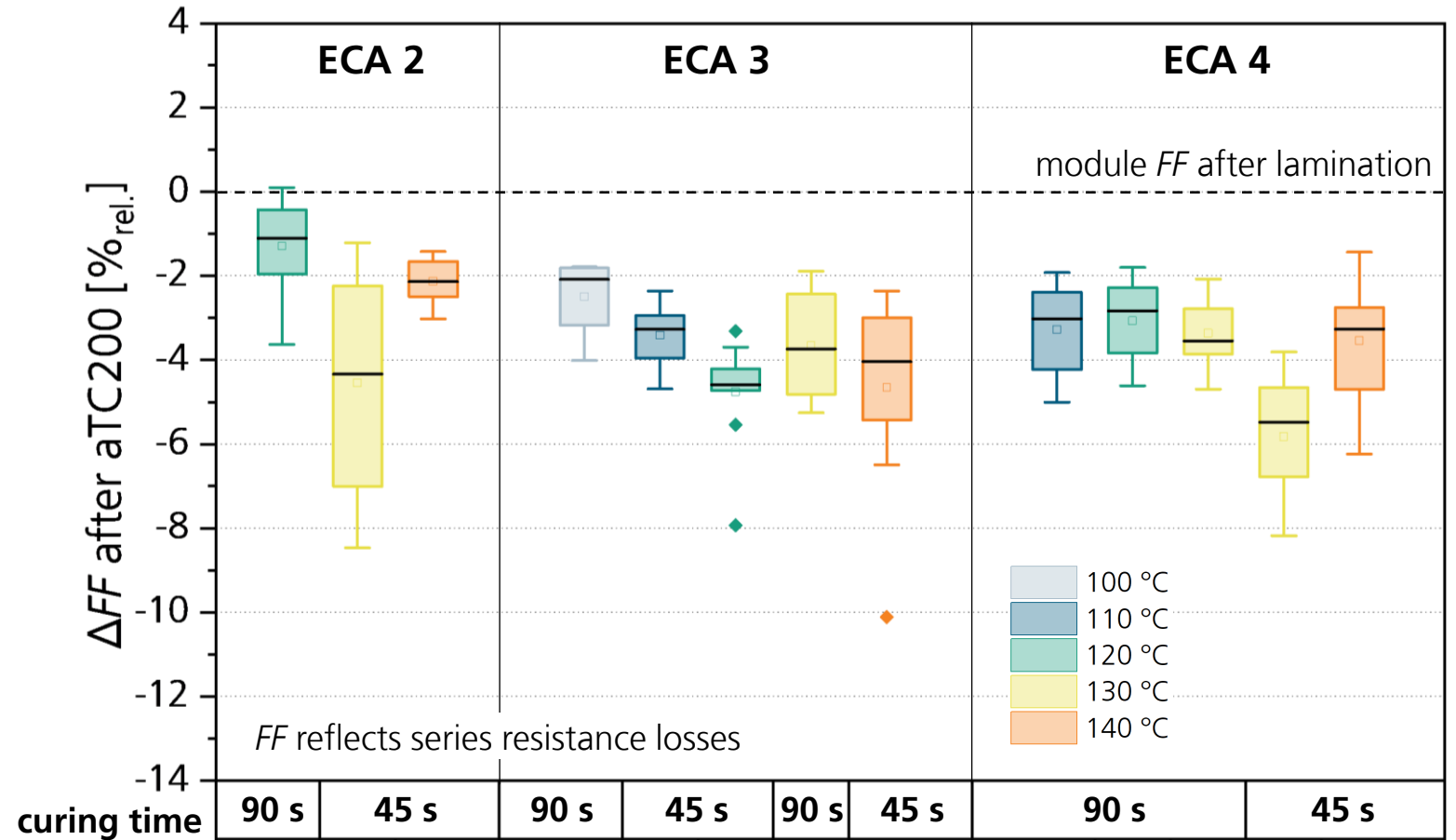
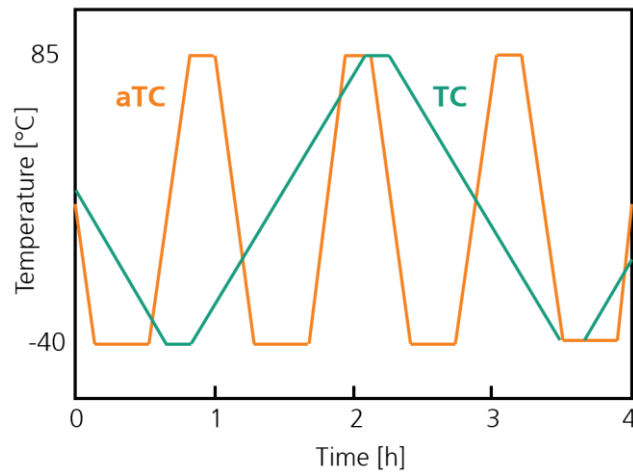
- Processing at PVST-compatible temperatures under 1 min is possible
- Behaviour of the ECA is product-specific
- Each ECA has to be tested before introducing it in the production*



Performance in the Module

Reliability of the Low-Temperature ECA Interconnection

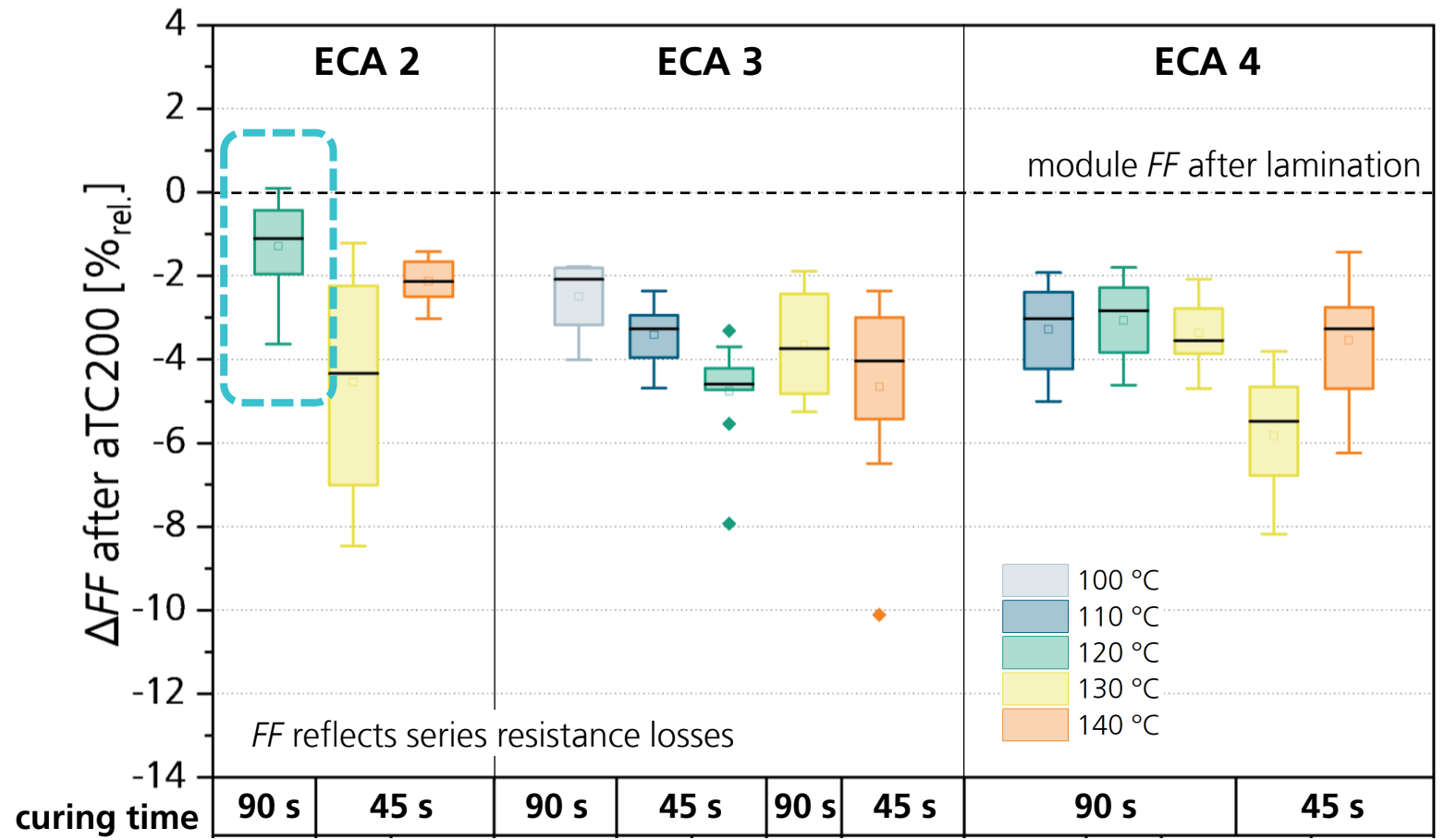
- Samples were exposed to accelerated thermal cycling ^[11] (aTC), 200 cycles
- All groups show fill factor loss after aTC200



Performance in the Module

Reliability of the Low-Temperature ECA Interconnection

- Least degradation after aTC200:
 - ECA-2 (17 wt% Ag) cured at 120 °C for 90 s

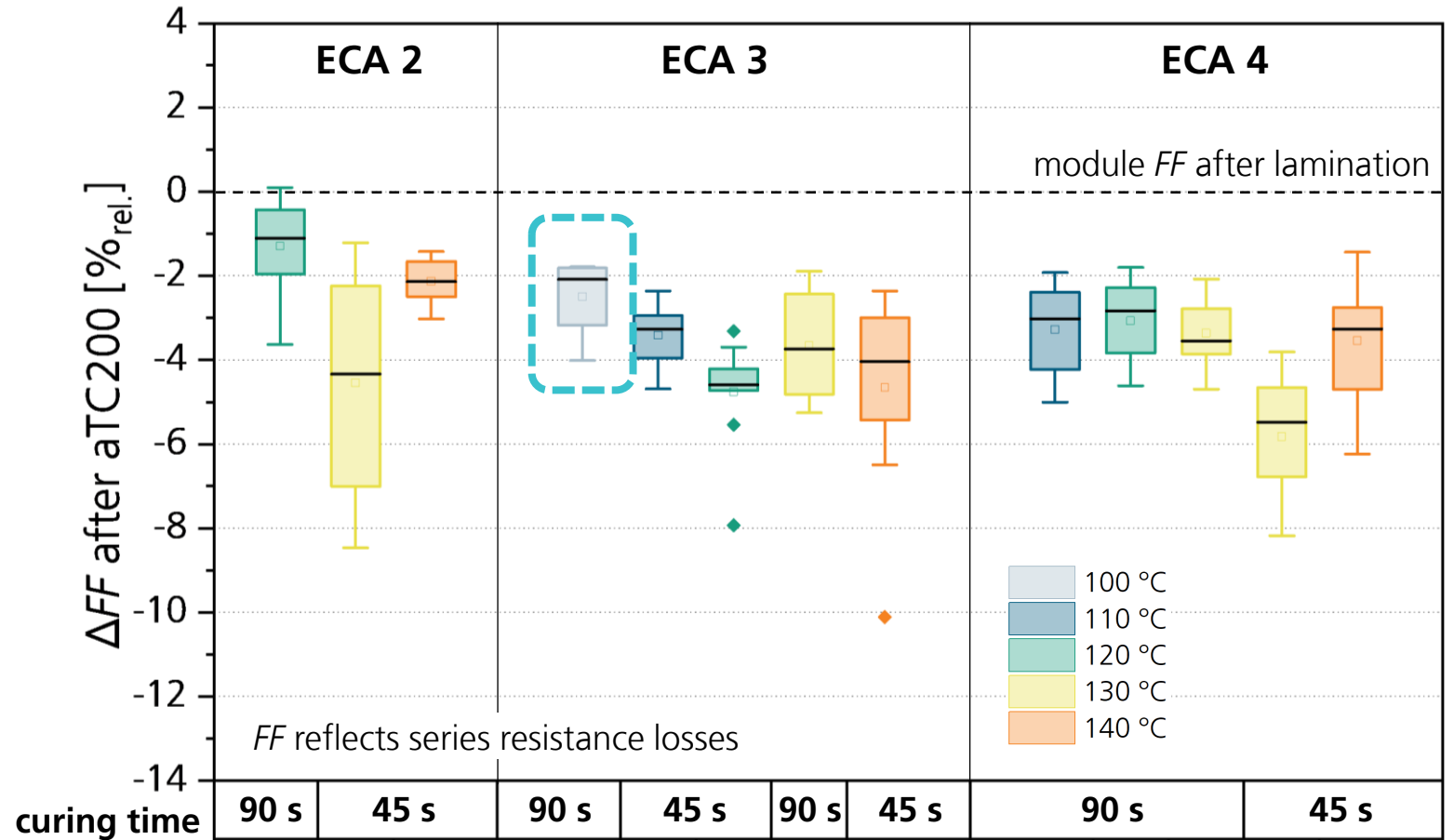


Performance in the Module

Reliability of the Low-Temperature ECA Interconnection

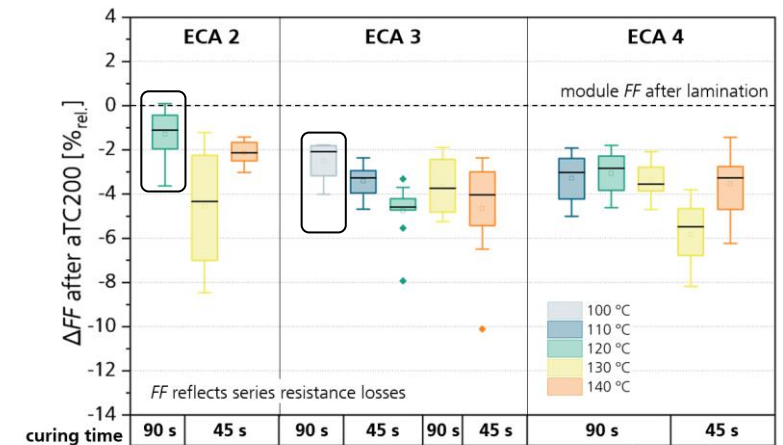
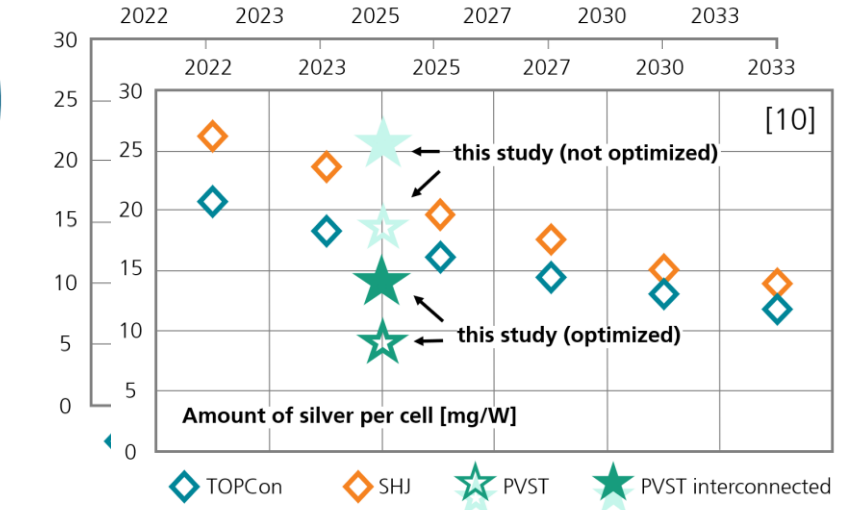
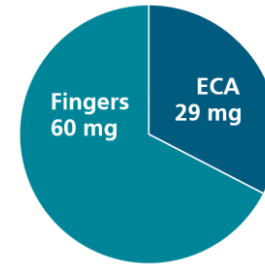
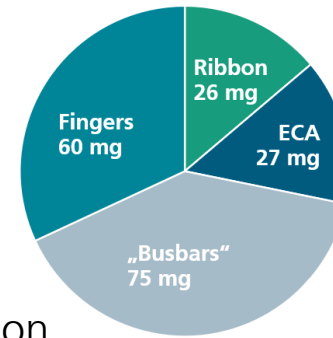
- Least degradation after aTC200:
 - ECA-2 (17 wt% Ag)
cured at 120 °C for 90 s

- Best combination of CTM* loss and least degradation:
 - ECA-3 (70 wt% Ag)
cured at 100 °C for 90 s



Summary

- Silver consumption for M6 PVST cell estimated ~ 19 mg Ag/W (~ 27 mg Ag/W including ECA interconnection) before optimization
- Silver reduction strategies can include
 - Replacement of Ag ribbon coating with Sn (-26 mg Ag/cell)
 - Optimization of busbar metallization and ECA application (-73 mg Ag/cell)
- Busbarless PVST cell with low-Ag ECA interconnection is estimated ~ 13 mg Ag/W
- Automatic ECA interconnection process at $T \leq 140 \text{ }^\circ\text{C}$ and $t \leq 90 \text{ sec}$ demonstrated
- Curing longer at lower temperatures is preferable
- ECA interconnection testing on busbarless SHJ cells with aTC200 show
 - Least degradation: ECA-2 (17 wt.% Ag)
 - Least CTM loss and degradation: ECA-3 (70 wt.% Ag)



Thank you for your attention!

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